- **5-Ω Switch Connection Between Two Ports**
- **TTL-Compatible Input Levels**
- **Bus Hold on Data Inputs/Outputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages**

description

The SN74CBTH16211 provides 24 bits of high-speed TTL-compatible bus switching. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

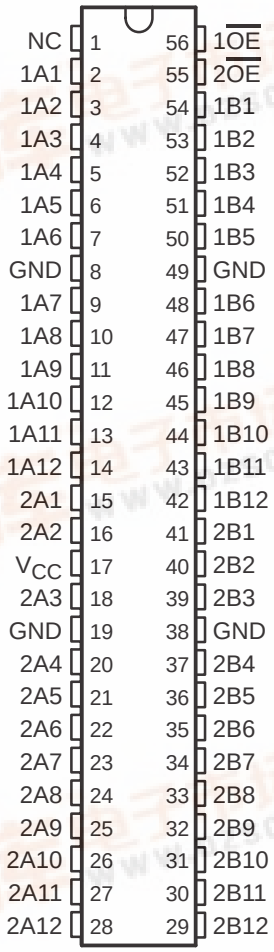
The device is organized as dual 12-bit bus switches with separate output-enable ($\overline{OE}$) inputs. It can be used as two 12-bit bus switches or one 24-bit bus switch. When $\overline{OE}$ is low, the associated 12-bit bus switch is on, and the A port is connected to the B port. When $\overline{OE}$ is high, the switch is open, and a high-impedance state exists between the two ports.

Active bus-hold circuitry is provided to hold unused or floating A and B ports at a valid logic level.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74CBTH16211 is characterized for operation from –40°C to 85°C.

DGG, DGV, OR DL PACKAGE
(TOP VIEW)

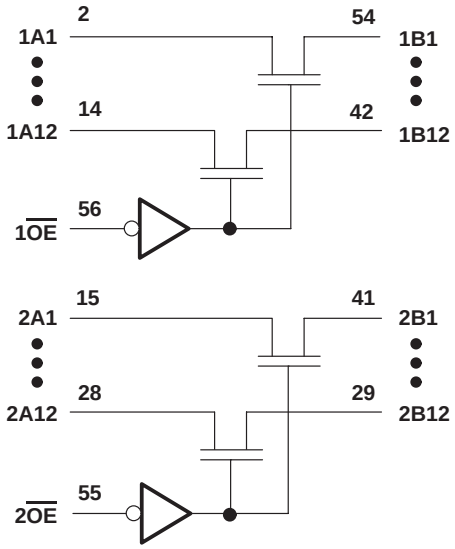


NC – No internal connection

FUNCTION TABLE
(each bus switch)

INPUT $\overline{OE}$	FUNCTION
L	A port = B port
H	Disconnect

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input voltage range, V_I (see Note 1) . . . . . –0.5 V to 7 V
Continuous channel current . . . . . 128 mA
Input clamp current, I_{IK} ($V_I < 0$) . . . . . –50 mA
Package thermal impedance, θ_{JA} (see Note 2): DGG package . . . . . 64°C/W
DGV package . . . . . 48°C/W
DL package . . . . . 56°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	4	5.5	V
V_{IH}	High-level control input voltage	2		V
V_{IL}	Low-level control input voltage		0.8	V
T_A	Operating free-air temperature	–40	85	°C

NOTE 3: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP†	MAX	UNIT
V_{IK}		V_{CC} = 4.5 V,	I_I = –18 mA				–1.2	V
I_I	Control inputs	V_{CC} = 0 V,	V_I = 5.5 V				±10	µA
	All inputs	V_{CC} = 5.5 V,	V_I = 5.5 V or GND				±10	
I_{BHL}‡		V_{CC} = 4.5 V,	V_I = 0.8 V		100			µA
I_{BHH}§		V_{CC} = 4.5 V,	V_I = 2 V		–100			µA
I_{BHLO}¶		V_{CC} = 5.5 V,	V_I = 0 to 5.5 V		500			µA
I_{BHHO}#		V_{CC} = 5.5 V,	V_I = 0 to 5.5 V		–500			µA
I_{CC}		V_{CC} = 5.5 V,	I_O = 0,	V_I = V_{CC} or GND			3	µA
ΔI_{CC}‖	Control inputs	V_{CC} = 5.5 V,	One input at 3.4 V,	Other inputs at V_{CC} or GND			2.5	mA
r_{on}☆		V_{CC} = 4 V, TYP at V_{CC} = 4 V	V_I = 2.4 V,	I_I = 15 mA		14	20	Ω
		V_{CC} = 4.5 V	V_I = 0	I_I = 64 mA		5	7	
				I_I = 30 mA		5	7	
			V_I = 2.4 V,	I_I = 15 mA		8	12	

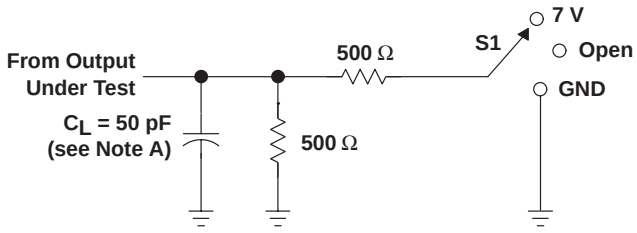
† All typical values are at V_{CC} = 5 V (unless otherwise noted), T_A = 25°C.
‡ The bus hold circuit can sink at least the minimum low sustaining current at V_{IL} max. I_{BHL} should be measured after lowering V_{IN} to GND and then raising it to V_{IL} max.
§ The bus hold circuit can source at least the minimum high sustaining current at V_{IH} min. I_{BHH} should be measured after raising V_{IN} to V_{CC} and then lowering it to V_{IH} min.
¶ An external driver must source at least I_{BHLO} to switch this node from low to high.
# An external driver must sink at least I_{BHHO} to switch this node from high to low.
‖ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.
☆ Measured by the voltage drop between the A and B terminals at the indicated current through the switch. On-state resistance is determined by the lowest voltage of the two (A or B) terminals.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4 V		V_{CC} = 5 V ± 0.5 V		UNIT
			MIN	MAX	MIN	MAX	
t_{pd}□	A or B	B or A		0.35		0.25	ns
t_{en}	$\overline{OE}$	A or B		9.9	1	9.6	ns
t_{dis}	$\overline{OE}$	A or B		9.5	1	8.3	ns

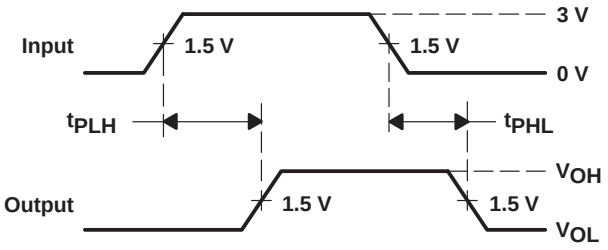
□ The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).

PARAMETER MEASUREMENT INFORMATION

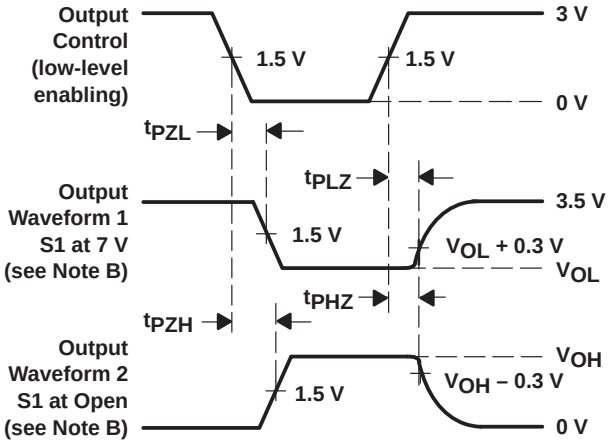


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
F. t_{PZL} and t_{PZH} are the same as t_{en}.
G. t_{PLH} and t_{PHL} are the same as t_{pd}.

Figure 1. Load Circuit and Voltage Waveforms

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